

**LMN22N10SF 100V N-Channel Enhancement Mode MOSFET****Features**

- $R_{DS(ON)} = 22m\Omega @ V_{GS} = 10V$
- $R_{DS(ON)} = 32m\Omega @ V_{GS} = 4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available
- SOP-8 package design

These devices are well suited for high efficiency fast switching applications.

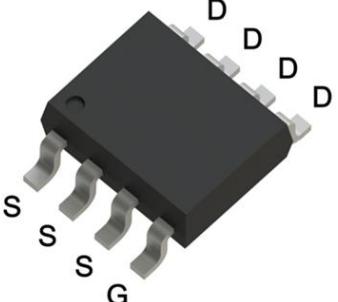
**Product Description**

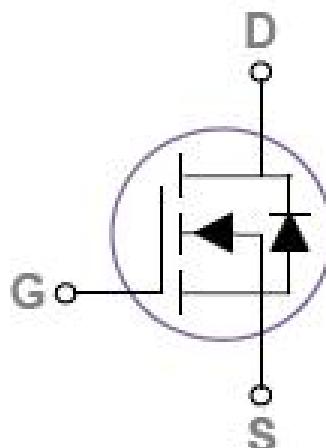
These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

**Applications**

- Networking
- Load Switch
- LED applications

**Pin Configuration**

LMN22N10SF (SOP-8)	
	
Pin	Description
1	Source
2	Source
3	Source
4	Gate
5	Drain
6	Drain
7	Drain
8	Drain



**LMN22N10SF**

**Ordering Information**

Part Number	P/N	PKG Code	Pb Free Code	Package	Quantity Reel
LMN22N10SF	LMN22N10	S	F	SOP-8	4000 pcs

**Marking Information**

Part Marking	Part Number	LFC code
22N10S XWMMMM	22N10S	XWMMMM

**Absolute Maximum Ratings**
(T<sub>A</sub>=25°C Unless otherwise noted)

Symbol	Parameter		Typical	Unit
V <sub>DS</sub>	Drain-Source Voltage		100	V
V <sub>GS</sub>	Gate-Source Voltage		±20	V
I <sub>D</sub>	Continuous Drain Current <sup>1</sup>	T <sub>A</sub> =25°C	7.3	A
		T <sub>A</sub> =70°C	5.8	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>		12	A
P <sub>D</sub>	Total Power Dissipation <sup>3</sup>	T <sub>A</sub> =25°C	2.5	W
		T <sub>A</sub> =70°C	1.6	
T <sub>J</sub>	Operating Junction Temperature Range		-50 to +150	°C
T <sub>STG</sub>	Storage Temperature Range		-50 to +150	°C
R <sub>θJC</sub>	Thermal Resistance-Junction to Case <sup>1</sup>		50	°C/W

**Note:**

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper.
2. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.
3. The power dissipation is limited by 150°C junction temperature.

**Electrical Characteristics**
(T<sub>A</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	100			V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	1	2	3	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			1	uA
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			7.3	A
I <sub>SM</sub>	Pulsed Source Current				30	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =10A		18	22	mΩ
		V <sub>GS</sub> =6V, I <sub>D</sub> =5A		18.7	24	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A		19.6	32	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A		14.5		S
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =1A			1	V
<b>Dynamic</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz		4708		pF
C <sub>oss</sub>	Output Capacitance			326		
C <sub>rss</sub>	Reverse Transfer Capacitance			247		
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz		1.6		Ω
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =80V, V <sub>GS</sub> =10V, I <sub>D</sub> =20A		75		nC
Q <sub>gs</sub>	Gate-Source Charge			15.5		
Q <sub>gd</sub>	Gate-Drain Charge			20.3		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =50V, I <sub>D</sub> =1A, V <sub>GS</sub> =10V, R <sub>G</sub> =6Ω		11.5		ns
T <sub>r</sub>	Turn-On Rise Time			29		
t <sub>d(off)</sub>	Turn-Off Delay Time			42		
T <sub>f</sub>	Turn-Off Fall Time			18		

### Typical Performance Characteristics

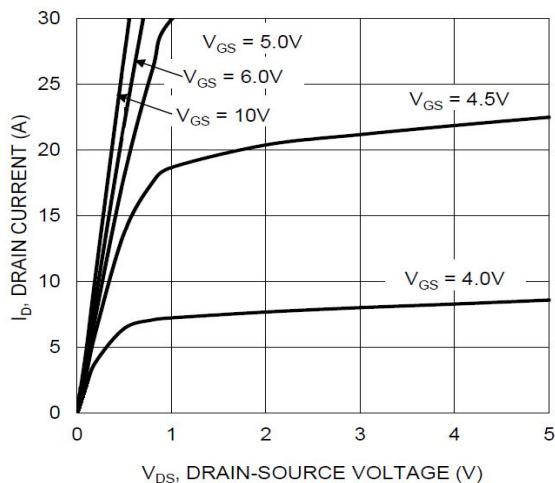


Fig.1 Typical Output Characteristics

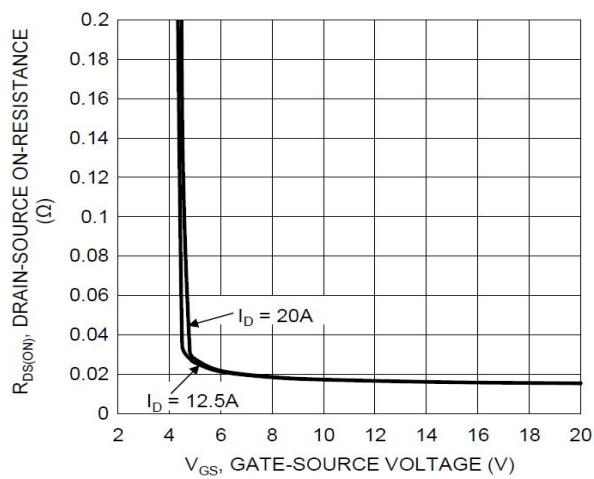


Fig.2 On-Resistance vs. Gate-Source Voltage

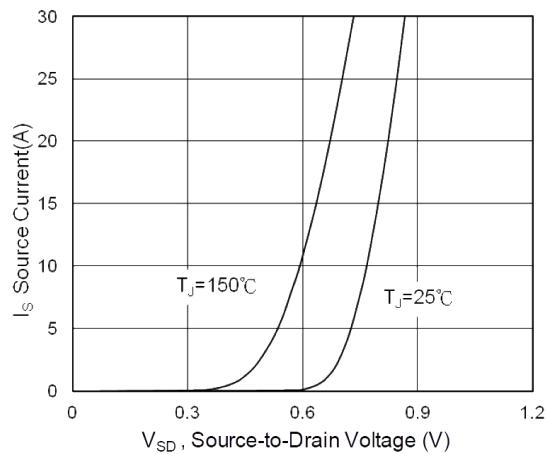


Fig.3 Diode Forward Voltage vs. Current

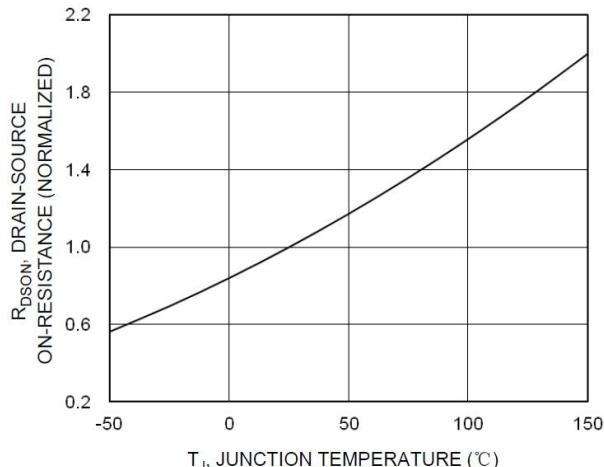


Fig.4 On-Resistance Variation with  $T_J$

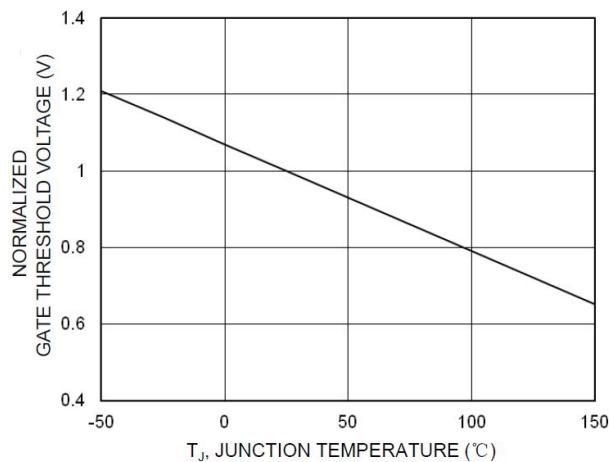


Fig.5 Gate Threshold Variation vs.  $T_J$

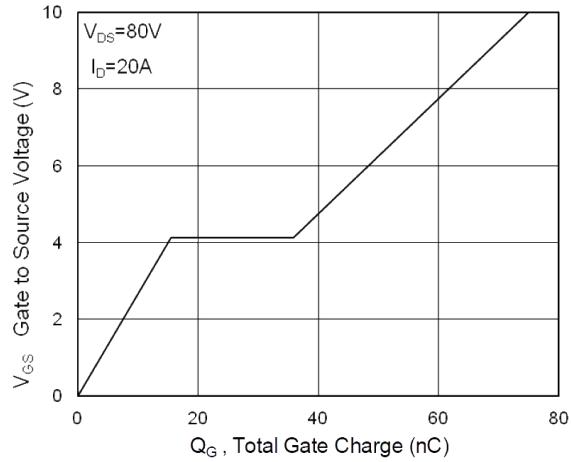
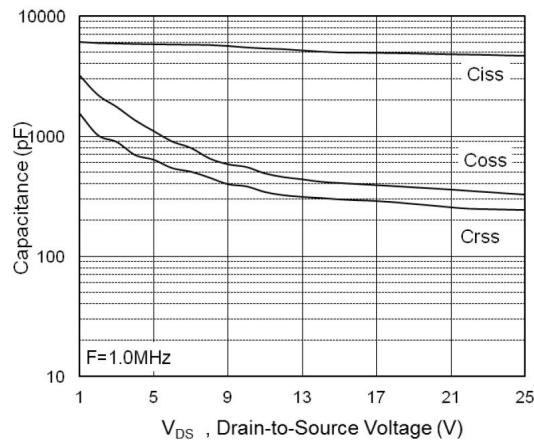
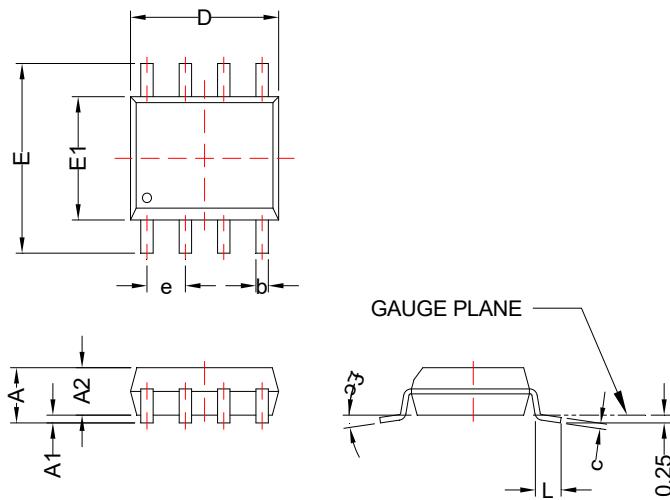


Fig.6 Gate Charge

**Typical Performance Characteristics (continue.)****Fig.7 Typical Capacitance**

**Package Dimension**
**SOP-8**


<b>Dimensions</b>				
<b>Symbol</b>	<b>Millimeters</b>		<b>Inches</b>	
	<b>Min</b>	<b>Max</b>	<b>Min</b>	<b>Max</b>
<b>A</b>	-	1.750	-	0.069
<b>A1</b>	0.100	0.250	0.004	0.010
<b>A2</b>	1.250	-	0.049	-
<b>b</b>	0.310	0.510	0.012	0.020
<b>c</b>	0.100	0.250	0.004	0.010
<b>D</b>	4.700	5.100	0.185	0.201
<b>E</b>	5.800	6.200	0.228	0.244
<b>E1</b>	3.800	4.000	0.150	0.157
<b>e</b>	1.270 BSC		0.050 BSC	
<b>L</b>	0.400	1.270	0.016	0.050
<b>θ</b>	0°	8°	0°	8°